

L Number	Hits	Search Text	DB	Time stamp
17	3	"6411859"	USPAT; US-PGPUB; EPO; DERWENT	2002/10/17 13:04
18	1	"6446022"	USPAT; US-PGPUB; EPO; DERWENT	2002/10/17 13:04
-	187	(report or monitor) and (wafer or semiconductor or semi-conductor or circuit) and (fault or (fault and detect\$3) or quality) and (700/108-110 700/121 716/4 716/19-21 702/81-84).cccls. and @PY<2000	USPAT; US-PGPUB; EPO; DERWENT	2002/10/15 13:34
-	248	(report or monitor) and (fault or (fault same detect\$3) or quality) and data and (700/108-110 700/121 716/4 716/19-21 702/81-84).cccls. and @PY<2000	USPAT; US-PGPUB; EPO; DERWENT	2002/10/15 12:34
-	19	(request or query) and (report or monitor) and (wafer or semiconductor or semi-conductor or circuit) and (fault or (fault and detect\$3)) and (700/108-110 700/121 716/4 716/19-21 702/81-84).cccls. and @PY<2000	USPAT; US-PGPUB; EPO; DERWENT	2002/10/15 13:13
-	80	(report or monitor\$4) and (wafer or semiconductor or semi-conductor or circuit) and (fault or (fault and defect\$3)) and (700/108-110 700/121 716/4 716/19-21 702/81-84).cccls. and @PY<2000	USPAT; US-PGPUB; EPO; DERWENT	2002/10/15 13:27
-	214	(report or monitor or status) and (wafer or semiconductor or semi-conductor or circuit) and (fault or (fault and defect\$3) or quality) and (700/108-110 700/121 716/4 716/19-21 702/81-84).cccls. and @PY<2000	USPAT; US-PGPUB; EPO; DERWENT	2002/10/15 13:36